

P54/74PCT257A/B, P54/74PCT258A/B DATA SELECTOR/MULTIPLEXER

PRELIMINARY

T-67-21-51

★ FEATURES

- Quad 2-line to 1-line Data Selector Multiplexer
- Full CMOS Implementation
- Low Power Operation
- $I_{OL} = 48 \text{ mA}$ (Commercial) and 32 mA (Military)
- 3-State Outputs
- Fully TTL Compatible Input and Output levels
- Produced with PACE Technology™
- Compact Pinout—16-Pin 300 mil DIP, SOIC

★ DESCRIPTION

The P54/74PCT257A/B and P54/74PCT258A/B have four identical 2-input multiplexers with 3-state outputs which select 4 bits of data from two sources under control of a common Data Select input (S). The I_0 inputs are selected when the Select input is LOW and the I_1 inputs are selected when the select input is HIGH. Data appears at the output in true noninverted form for the P54/74PCT257A/B and in the inverted form for the P54/74PCT258A/B from the selected outputs.

The 'PCT257 and 'PCT258 are logic implementation of a 4-pole, 2 position switch where the position of the switch is determined by the logic levels supplied to the select input.

Outputs are forced to a high-impedance "OFF" state when the Output Enable input ($\overline{OE}$) is HIGH.

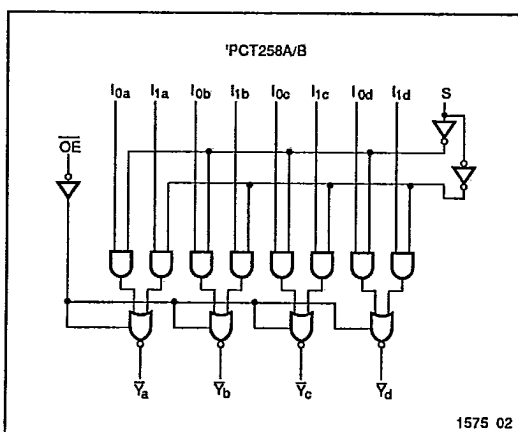
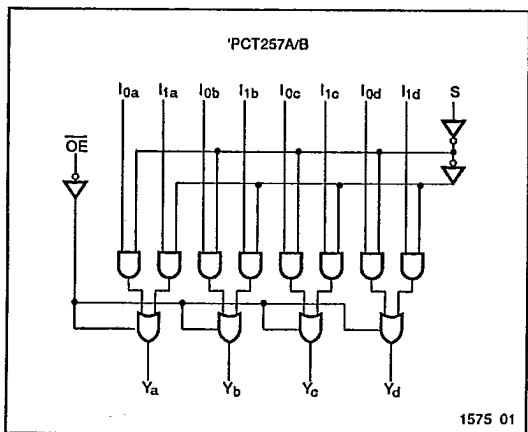
All but one device must be in the High-impedance state to avoid currents exceeding the maximum ratings if outputs are tied together. Design of the output enable signals must ensure that there is no overlap when outputs of 3-state devices are tied together.

The P54/74PCT257/258 is manufactured using PACE Technology™ which is Performance Advanced CMOS Engineered to use 0.8 micron effective channel lengths giving 500 picoseconds loaded *internal gate delays.

Pace Technology includes two-level metal and epitaxial substrates. In addition to very high performance and very high density, the technology features latch-up protection, single event upset protection, and is supported by a Class 1 environment volume production facility.

*For a fan-in/fan-out of 4, at 85°C junction temperature and 5.0V.

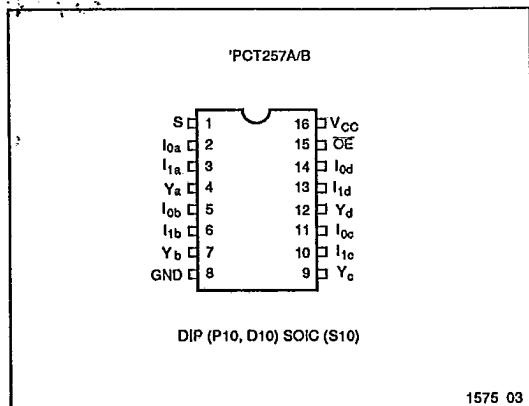
★ FUNCTIONAL BLOCK DIAGRAM



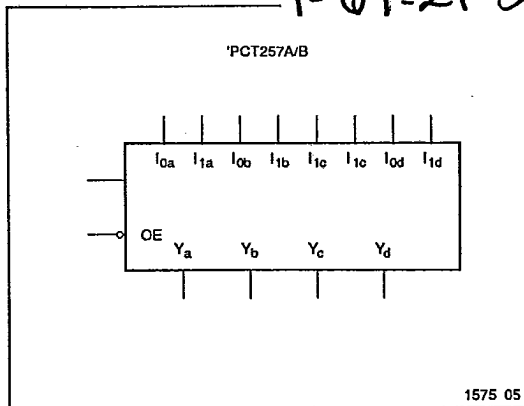
PERFORMANCE
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Means Quality, Service and Speed

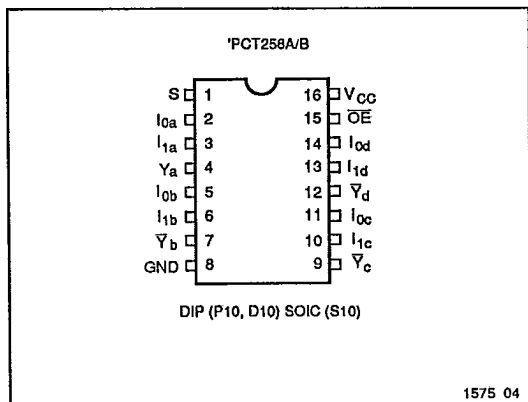
★ PIN CONFIGURATION



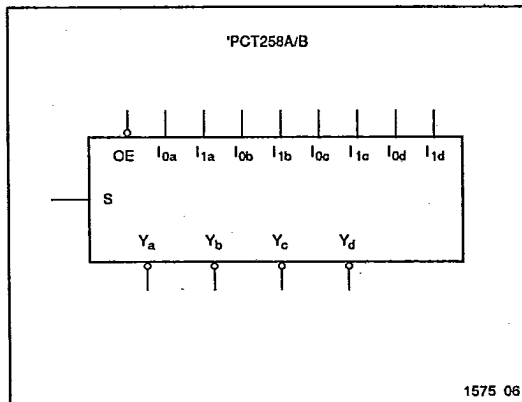
LOGIC DIAGRAM



PIN CONFIGURATION



LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS^{1,2}

Symbol	Parameter	Value	Unit
T_{STG}	Storage Temperature	-65 to +150	°C
T_A	Ambient Temperature Under Bias	-55 to +125	°C
V_{CC}	V_{CC} Potential to Ground	-0.5 to +7.0	V
I_{IN}	Input Current	-30 to +5.0	mA

Notes:

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1. Operation beyond the limits set forth in the above table may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range.

RECOMMENDED OPERATING CONDITIONS

Free Air Ambient Temperature	Min	Max
Military	-55°C	+125°C
Commercial	0°C	+70°C

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Symbol	Parameter	Value	Unit
I_{OUTPUT}	Current Applied to Output	100	mA
V_{IN}	Input Voltage	-0.5 to $V_{CC} + 0.5$	V
V_{OUT}	Voltage Applied to Output	-0.5 to $V_{CC} + 0.5$	V

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2. Unused Inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.

Supply Voltage (V_{CC})	Min	Max
Military	+4.5V	+5.5V
Commercial	+4.75V	+5.25V

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DC ELECTRICAL CHARACTERISTICS (Over recommended operating conditions)

Symbol	Parameter	Min	Typ ¹	Max	Units	V_{CC}	Conditions
V_{IH}	Input HIGH Voltage	2.0		$V_{CC} + 0.5$	V		
V_{IL}	Input LOW Voltage	-0.5		0.8	V		
V_H	Hysteresis		.35		V		All inputs
V_{CD}	Input Clamp Diode Voltage			-1.2	V	MIN	$I_{IN} = -18\text{mA}$
V_{OH}	Output HIGH Voltage	$V_{CC} = 3\text{V}, V_{IN} = 0.2\text{V}, \text{ or } V_{CC} - 0.2\text{V}$		$V_{CC} - 0.2$	V		$I_{OH} = -32\mu\text{A}$
		Military/Commercial (CMOS)		$V_{CC} - 0.2$	V	MIN	$I_{OH} = -300\mu\text{A}$
		Military (TTL)		2.4	V	MIN	$I_{OH} = -12\text{mA}$
		Commercial (TTL)		2.7	V	MIN	$I_{OH} = -15\text{mA}$
V_{OL}	Output LOW Voltage	$V_{CC} = 3\text{V}, V_{IN} = 0.2\text{V}, \text{ or } V_{CC} - 0.2\text{V}$		0.2	V		$I_{OL} = 300\mu\text{A}$
		Military/Commercial (CMOS)		0.2	V	MIN	$I_{OL} = 300\mu\text{A}$
		Military (TTL)		0.5	V	MIN	$I_{OL} = 32\text{mA}$
		Commercial (TTL)		0.5	V	MIN	$I_{OL} = 48\text{mA}$
I_{IH}	Input HIGH Current			5	μA	MAX	$V_{IN} = V_{CC}$
I_{IL}	Input LOW Current			-5	μA	MAX	$V_{IN} = \text{GND}$
I_{IH}	Input HIGH Current ³			5	μA	MAX	$V_{IN} = 2.7\text{V}$
I_{IL}	Input LOW Current ³			-5	μA	MAX	$V_{IN} = 0.5\text{V}$
I_{OZH}	Off State I_{OUT} HIGH-Level Voltage Applied			10	μA	MAX	$V_{OUT} = V_{CC}$
I_{OZL}	Off State I_{OUT} LOW-Level Voltage Applied			-10	μA	MAX	$V_{OUT} = \text{GND}$
I_{OZH}	Off State I_{OUT} HIGH-Level Voltage Applied ³			10	μA	MAX	$V_{OUT} = 2.7\text{V}$
I_{OZL}	Off State I_{OUT} LOW-Level Voltage Applied ³			-10	μA	MAX	$V_{OUT} = 0.5\text{V}$
I_{OS}	Output Short Circuit Current ²	-60			mA	MAX	$V_{OUT} = 0.0\text{V}$
C_{IN}	Input Capacitance ³		5	10	pF	MAX	All inputs
C_{OUT}	Output Capacitance ³		9	12	pF	MAX	All outputs

Notes:

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1. Typical limits are at $V_{CC} = 5.0\text{V}$, $T_A = +25^\circ\text{C}$ ambient.

2. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect

operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

3. This parameter is guaranteed but not tested.



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DC CHARACTERISTICS (Over recommended operating conditions unless otherwise specified.)

Symbol	Parameter	Typ ¹	Max	Units	Conditions
I_{CCO}	Quiescent Power Supply Current (CMOS inputs) Com'l Mil	.003 .003	0.3 0.5	mA mA	$V_{CC} = \text{MAX}, V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V, f = 0$, Outputs Open
I_{CCAT}	Quiescent Power Supply Current (TTL inputs)		2.0	mA	$V_{CC} = \text{MAX}, V_{IN} = 3.4V^2$, $f = 0$, Outputs Open
I_{CCD}	Dynamic Power Supply Current ³		0.25	mA/ mHz	$V_{CC} = \text{MAX}$, One Input Toggling, 50% Duty Cycle, $\overline{OE} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$, Outputs Open
I_{CC}	Total Power Supply Current ⁵		4.0	mA	$V_{CC} = \text{MAX}$, 50% Duty Cycle, Outputs Open, One Input Toggling at $f_1 = 5\text{MHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
			6.0	mA	$V_{CC} = \text{MAX}$, 50% Duty Cycle, Outputs Open, One Input Toggling at $f_1 = 5\text{MHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$
			7.8 ⁴	mA	$V_{CC} = \text{MAX}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 2.5\text{MHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
			16.8 ⁴	mA	$V_{CC} = \text{MAX}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 2.5\text{MHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$

Notes:

- Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient and maximum loading.
- Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_{CC} = I_{CCO} + I_{CCAT} + I_{CCD}$
 $I_{CC} = I_{CCO} + I_{CCAT} + I_{CCD}$
 $I_{CCO} = \text{Quiescent Current with CMOS input levels}$

 I_{CCAT} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

 D_H = Duty Cycle for TTL Inputs High

 N_T = Number of TTL Inputs at D_H
 I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

 f_0 = Clock Frequency for Register Devices (Zero for Non-Register Devices)

 f_1 = Input Frequency

 N_1 = Number of Inputs at f_1

All currents are in milliamps and all frequencies are in megahertz.

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FUNCTION TABLE

Inputs				Output	
$\overline{OE}$	S	I_0	I_1	Y	$\overline{Y}$
H	X	X	X	Z	Z
L	H	X	L	L	H
L	H	X	H	H	L
L	L	L	X	L	H
L	L	H	X	H	L

H = High voltage level

L = Low voltage level

X = Don't care

Z = High impedance (OFF) state

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DEFINITION OF FUNCTIONAL TERMS

Pins	Description
$I_{0n} - I_{1n}$	Data inputs
S	Common select input
$\overline{OE}$	Enable input (Active-Low)
$Y_a - Y_d$	Data outputs

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AC CHARACTERISTICS

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Sym.	Parameter	P54/74PCT257A P54/74PCT258A					P54/74PCT257B P54/74PCT258B					Units	Fig. No.
		$T_A=+25^\circ\text{C}$ $V_{CC}=+5.0\text{V}$		MIL		COM'L	$T_A=+25^\circ\text{C}$ $V_{CC}=+5.0\text{V}$		MIL		COM'L		
		Typ.	Min. ¹	Max.	Min. ¹	Max.	Typ.	Min. ¹	Max.	Min. ¹	Max.		
t_{PLH} t_{PHL}	Propagation Delay I_{in} to Y_n 'PCT257	4.5 3.5			3.0 2.0	7.0 6.0						ns ns	1 3
t_{PLH} t_{PHL}	Propagation Delay S to Y_n 'PCT257	7.5 5.5			5.0 4.0	10.5 8.0						ns ns	1 3
t_{PZH} t_{PZL}	Output Enable time to High or Low 'PCT257	6.5 6.0			4.5 4.5	8.5 8.5						ns ns	1, 7, 8
t_{PHZ} t_{PLZ}	Output Disable time from High or Low 'PCT257	4.0 3.5			2.0 2.0	6.0 6.0						ns ns	1, 7, 8
t_{PLH} t_{PHL}	Propagation Delay I_n to $\bar{Y}_n$ 'PCT258	4.5 2.5			2.5 1.0	7.0 4.5						ns ns	1 2
t_{PLH} t_{PHL}	Propagation Delay S_n to $\bar{Y}_n$ 'PCT258	6.5 6.0			3.5 2.5	9.0 9.0						ns ns	1 5
t_{PZH} t_{PZL}	Output Enable time to High or Low 'PCT258	6.0 6.5			3.5 3.5	8.5 8.5						ns ns	1, 7, 8
t_{PHZ} t_{PLZ}	Output Disable time from High or Low 'PCT258	3.5 3.5			2.0 2.0	6.5 6.0						ns ns	1, 7, 8

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ORDERING INFORMATION

PxxPCT	xxxx	x	x	x	
Temp. Class	Device type	Package	Temperature	Processing	
				B	MIL-STD-883, Class B
				C	0°C to +70°C
				M	-55°C to +125°C
				P	Plastic DIP
				D	CERDIP
				S	Small Outline IC
				L	Leadless Chip Carrier
				257 A	Quad 2-line to 1-line Data Selector/Multiplexer (Non-inverting)
				258 A	Quad 2-line to 1-line Data Selector/Multiplexer (Inverting)
				257 B	Fast Quad 2-line to 1-line Data Selector/Multiplexer (Non-inverting)
				258 B	Fast Quad 2-line to 1-line Data Selector/Multiplexer (Inverting)
				74	Commercial
				54	Military

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